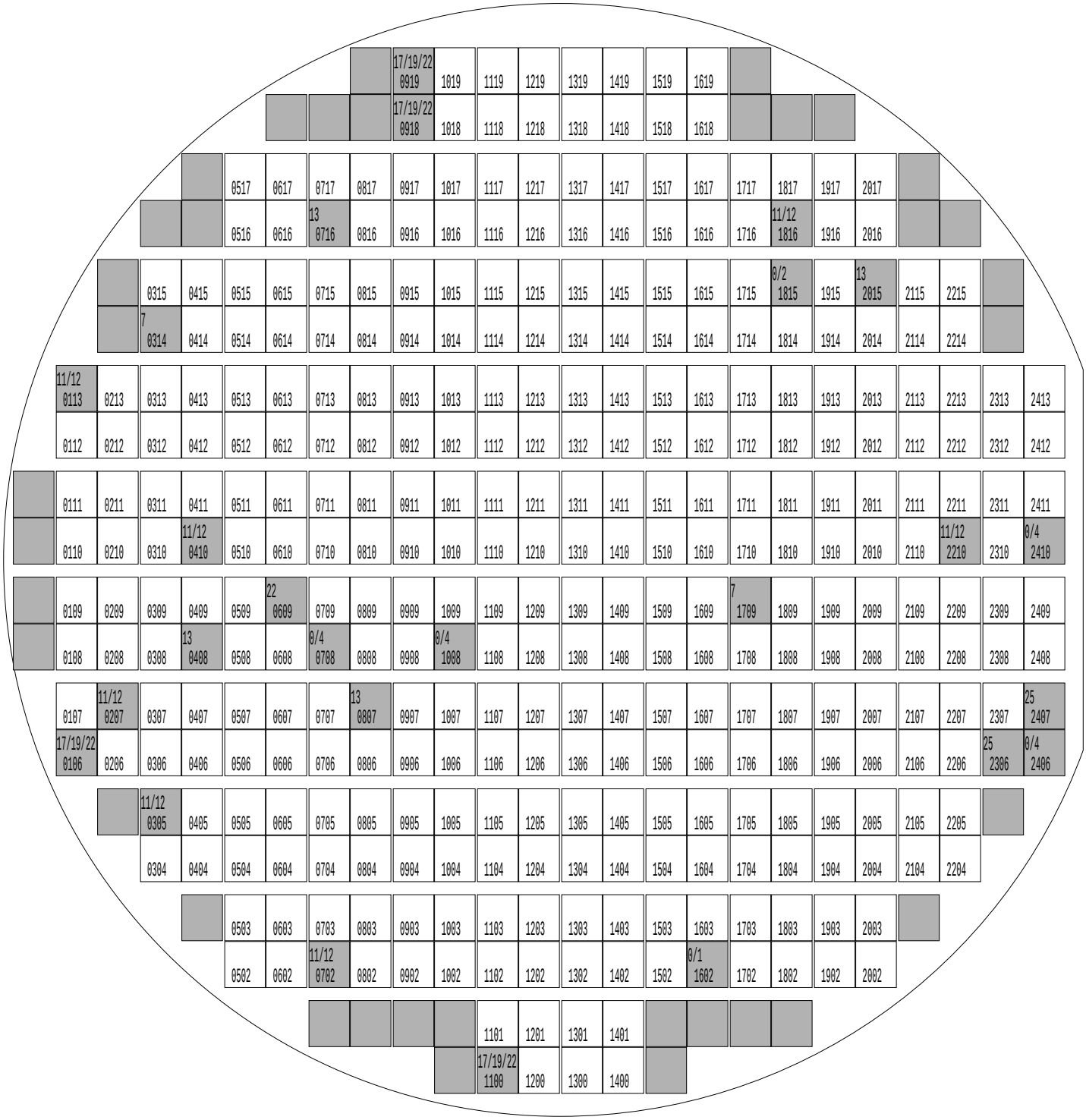
# Wafer Map: L122PCT

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|---|---|
| Date probed: | Tue 08 Jul 2003 |
| Chips passed: | 334/360 |
| Yield: | 93% |
| | |
| Digital failures: | 8 |
| Power supply failures: | 2 |
| Channel defects (Peds & Cal): | 12 |
| Pipeline defects: | 4 |